

Normally – OFF Silicon Carbide Junction Transistor

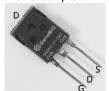
 V_{DS} = 1700 V $V_{DS(ON)}$ = 1.9 V I_{D} = 4 A $R_{DS(ON)}$ = 480 m Ω

Features

- 175 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- · Positive temperature coefficient for easy paralleling
- Low gate charge
- · Low intrinsic capacitance

Package

• RoHS Compliant





TO-247AB

Advantages

- SiC transistor most compatible with existing Si gate-drivers
- · Low switching losses
- Higher efficiency
- High temperature operation
- · High short circuit withstand capability

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- · Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Absolute Maximum Ratings

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V_{DS}	V _{GS} = 0 V	1700	V
Continuous Drain Current	I _D	T _{C,MAX} = 95 °C	4	Α
Gate Peak Current	I_{GM}		5	Α
Turn-Off Safe Operating Area	RBSOA	T_{VJ} = 175 °C, I_{G} = 1 A, Clamped Inductive Load	$I_{D,max} = 4$	Α
Short Circuit Safe Operating Area	SCSOA	T_{VJ} = 175 °C, I_G = 1 A, V_{DS} = 1200 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	V_{SG}		30	V
Reverse Drain – Source Voltage	V_{SD}		50	V
Power Dissipation	P _{tot}	T _C = 25 °C	91	W
Storage Temperature	T _{stg}		-55 to 175	°C

Electrical Characteristics

Davamatan	O. mah al	Conditions	Values			
Parameter	Symbol	Conditions -	min.	typ.	max.	Unit
On Characteristics						
		I _D = 4 A, I _G = 250 mA, T _j = 25 °C		1.9	2.3	
Drain – Source On Voltage	$V_{DS(ON)}$	$I_D = 4 \text{ A}, I_G = 500 \text{ mA}, T_j = 125 ^{\circ}\text{C}$		3.3	4.0	V
-		$I_D = 4 \text{ A}, I_G = 500 \text{ mA}, T_j = 175 °C$		4.5	5.5	
Drain – Source On Resistance		I _D = 4 A, I _G = 250 mA, T _i = 25 °C		480		
	$R_{DS(ON)}$	$I_D = 4 \text{ A}, I_G = 500 \text{ mA}, T_i = 125 ^{\circ}\text{C}$		830		mΩ
		$I_D = 4 \text{ A}, I_G = 500 \text{ mA}, T_i = 175 °C$		1130		
Cata Farward Valtage	$V_{GS(FWD)}$	I _G = 500 mA, T _j = 25 °C		3.3		1/
Gate Forward Voltage		$I_G = 500 \text{ mA}, T_i = 175 ^{\circ}\text{C}$		3.2		V
DC Comment Cain	0	V _{DS} = 5 V, I _D = 4 A, T _i = 25 °C	50	58		
DC Current Gain	β	$V_{DS} = 5 \text{ V}, I_D = 4 \text{ A}, T_j = 175 °C$		35		
Off Characteristics						
		$V_R = 1700 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25 \text{ °C}$		0.2	10	
Drain Leakage Current	I_{DSS}	$V_R = 1700 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 125 ^{\circ}\text{C}$		0.3	50	μΑ
-		$V_R = 1700 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 175 ^{\circ}\text{C}$		1.0	100	

Gate Leakage Current

V_{SG} = 20 V, T_j = 25 °C

nΑ

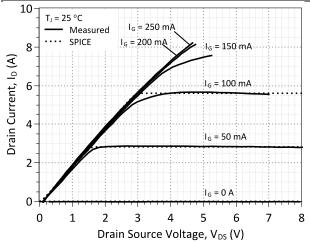
20



Electrical Characteristics

Parameter	Symbol	Conditions -	Values			Unit
- al allietei	Зуппоп	Conditions	min.	typ.	max.	Oilit
Capacitance Characteristics						
Gate-Source Capacitance	C_{gs}	V _{GS} = 0 V, f = 1 MHz		340		pF
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}, V_{D} = 1 \text{ V}, f = 1 \text{ MHz}$		460		pF
Reverse Transfer/Output Capacitance	C _{rss} /C _{oss}	V _D = 1 V, f = 1 MHz		120		pF
Switching Characteristics						
Turn On Delay Time	$t_{d(on)}$	T _i = 25 °C, V _{DS} = 1100 V, I _D = 4 A,		35		ns
Rise Time	t _r	Single-Level Gate Drive,		30		ns
Turn Off Delay Time	$t_{d(off)}$	$R_G = 1.5 \Omega, C_G = 9 \text{ nF},$ $V_{CC} = 15 \text{ V}, V_{EE} = -8 \text{ V},$ IXDD614 Gate Drive IC, $L = 1.05 \text{ mH}, \text{ FWD} = \text{GB05SLT12},$ Refer to Fig. 15 for gate current		60		ns
Fall Time	t _f			50		ns
Turn-On Energy Per Pulse	E _{on}			320		μJ
Turn-Off Energy Per Pulse	E_{off}			60		μJ
Total Switching Energy	E_{ts}	waveform		380		μJ
Turn On Delay Time	$t_{d(on)}$	$T_i = 175 ^{\circ}\text{C}, V_{DS} = 1100 ^{\circ}\text{V}, I_D = 4 ^{\circ}\text{A},$		30		ns
Rise Time	t _r	Single-Level Gate Drive,		15		ns
Turn Off Delay Time	$t_{d(off)}$	$R_G = 1.5 \Omega, C_G = 9 nF,$		75		ns
Fall Time	t _f	V_{CC} = 15 V, V_{EE} = -8 V, IXDD614 Gate Drive IC.		60		ns
Turn-On Energy Per Pulse	E _{on}	L = 1.05 mH, FWD = GB05SLT12, Refer to Fig. 15 for gate current		170		μJ
Turn-Off Energy Per Pulse	E _{off}			75		μJ
Total Switching Energy	E _{ts}	waveform		245		μJ
Thermal Characteristics						
Thermal resistance, junction - case	R _{thJC}			1.64		°C/W

Figures





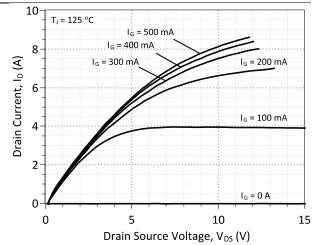


Figure 2: Typical Output Characteristics at 125 °C



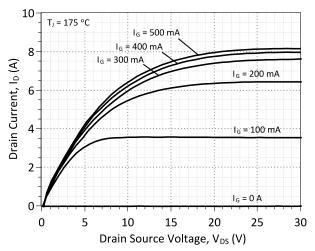


Figure 3: Typical Output Characteristics at 175 °C

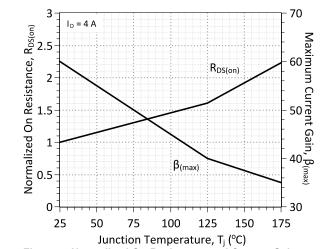


Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

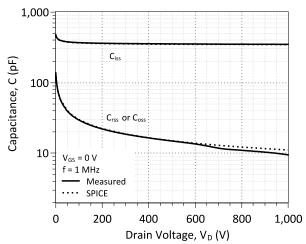


Figure 7: Capacitance Characteristics

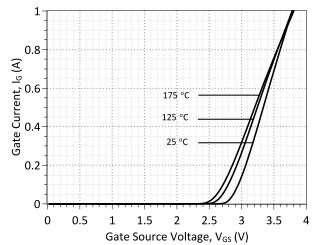


Figure 4: Typical Gate Source I-V Characteristics vs.
Temperature

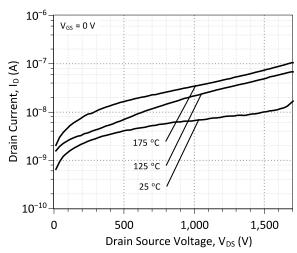


Figure 6: Typical Blocking Characteristics

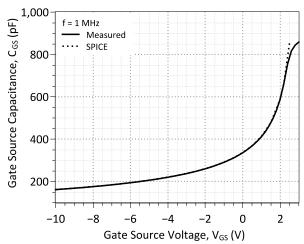


Figure 8: Capacitance Characteristics

Pg3 of 8



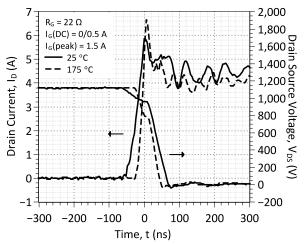


Figure 9: Typical Hard-switched Turn On Waveforms

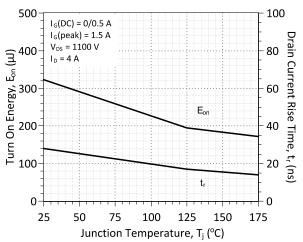


Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

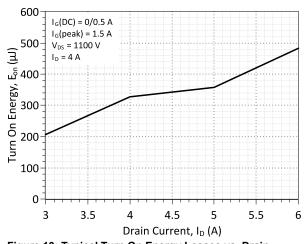


Figure 13: Typical Turn On Energy Losses vs. Drain Current

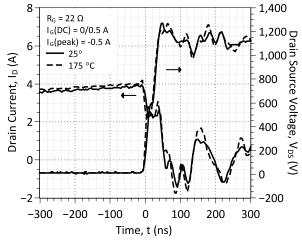


Figure 10: Typical Hard-switched Turn Off Waveforms

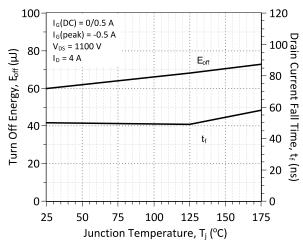


Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

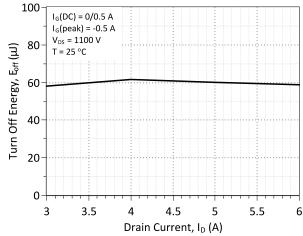


Figure 14: Typical Turn Off Energy Losses vs. Drain Current



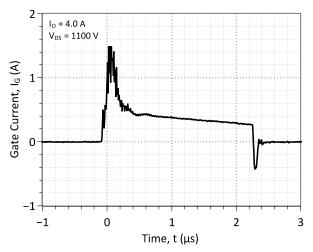


Figure 15: Typical Gate Current Waveform

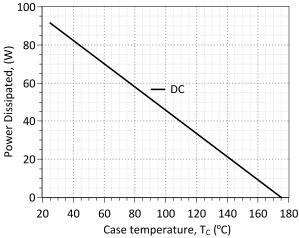


Figure 17: Power Derating Curve

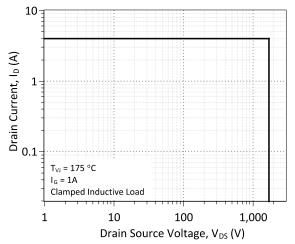


Figure 19: Turn-Off Safe Operating Area

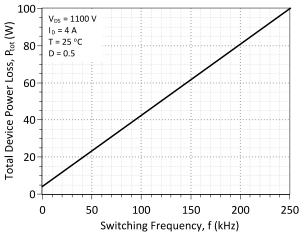


Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency ¹

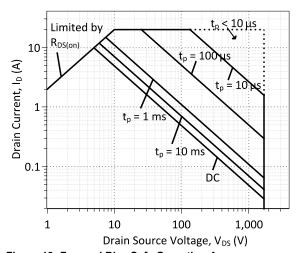


Figure 18: Forward Bias Safe Operating Area

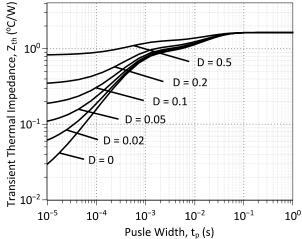


Figure 20: Transient Thermal Impedance

^{1 –} Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.



Commercial Gate Drivers Compatible with GA04JT17-247

				Available Features				
Manufacturer	Part Number	Peak Current Capability	Peak Current Width Control	Optical Signal Isolation	Desaturation Detection	Under Voltage Lockout		
Avago Tech.	ACPL-322J	2.5	_	✓	✓	✓		
IXYS	IXD_604	4.0	-	-	-	_		
IXYS	IXD_609	9.0	-	_	_	_		
IXYS	IXD_614	14.0	-	-	-	-		
Micrel	MIC4452YN	12.0	-	-	-	_		
Microsemi	LX1780QLQ	15.0	✓	-	-	✓		
Texas Instruments	UCC27322	9.0	_	_	_	_		

SiC SJTs do NOT require a current-driven gate driver. Modern Si IGBT drivers offer sufficient gate currents to drive SJTs. This is a partial list of widely available commercial Silicon IGBT/MOSFET gate drivers which may be used to drive the GA04JT17-247. Specific product information including advanced features and pinouts should be obtained from the individual product manufacturer's websites.

The GA04JT17-247 can be driven similar to silicon IGBTs or MOSFETs in which a gate driver IC is used to supply positive gate current peaks to the device at turn-on and negative current peaks at turn-off. Unlike the IGBT or MOSFET, the GA04JT17-247 also requires a continuous gate current for the device to remain on after the initial current peak. An example gate current waveform for the GA04JT17-247 is shown in Fig. 15.

Single-Level SJT Gate Drive

Producing the necessary gate current peaks and continuous currents can be accomplished by using a gate drive circuit shown in Fig. 21. The gate driver output node is connected to an NPN/PNP silicon BJT pair in a totem pole configuration which provide gate current to the SJT gate. The NPN/PNP pair are controlled by the gate drive IC connected through base resistor R_b . The pair's output at node N_t is connected to gate resistor R_G and capacitor C_G placed in parallel and connected to the SJT gate terminal. The gate resistor determines the continuous gate current. The gate capacitor produces positive and negative current peaks, which enable fast charging and discharging of the SJT's terminal capacitances. Additional detail on the single-level SJT gate driving technique is discussed in GeneSiC Semiconductor Application Note AN-10A. (http://www.genesicsemi.com/index.php/references/notes)

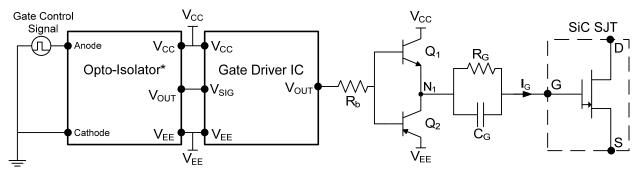


Figure 21: Single-Level SJT Gate Diver Configuration (* External signal isolation is recommended for non-isolated gate driver ICs.)

Single-Level Gate Drive Conditions

Parameter	Cumbal	Conditions	Canditions Val			Unit
Parameter	Symbol	Conditions	Min.	Optimum	Max.	
Supply Voltage	V _{cc}			15	20	V
Negative Supply Voltage	V_{EE}		-10	-5		V
Output Current, Peak	I _{OUT, pk}	Package Limited,	1.0	1.5		Α
Output Current, Continuous	I _{OUT}	I _D = 4.0 A, T = 175 °C	0.3	0.4		Α

Output Gate Components

Gate Resistance	R_{G}	$V_{CC} = 15 \text{ V}, I_{G} \approx 0.4 \text{ A}, T = 175 ^{\circ}\text{C}$	15	25	Ω
Gate Capacitance	C_G	$V_{CC} = 15 \text{ V I}_{G,pk} \approx 1.5 \text{ A}, \text{ T} = 175 ^{\circ}\text{C}$	5	9	nF
Base Resistor	R₀			10	Ω
NPN/PNP BJT Output Buffer	Q_1, Q_2	2N6107/2N6292	pair or	equivalent	**

^{** -} Complimentary BJT pair with $I_C \ge 5$ A and $V_{CEO} \ge 60$ V



Two-Level SJT Gate Drive

The GA04JT17-247 can also be driven with a gate drive circuit shown in Fig. 22, in which two gate drive ICs and NPN/PNP pairs are operated with different supply voltage (V_{CC}) levels in order to minimize gate drive losses. By using a separate lower voltage output gate driver IC connected to gate resistor R_G , the power consumption of the continuous current is reduced. Additional detail on the two-level SJT gate driving technique is discussed in GeneSiC Semiconductor Application Note AN-10B. (http://www.genesicsemi.com/index.php/references/notes)

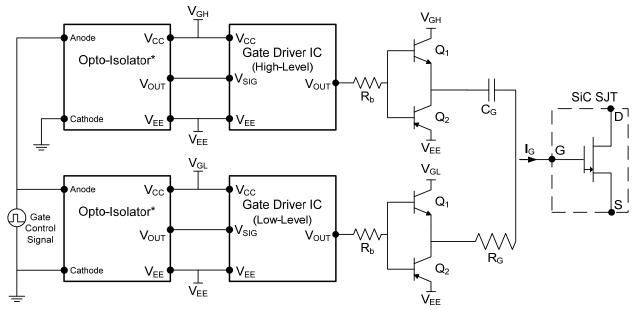


Figure 22: Two-Level SJT Gate Diver Configuration for Reduced Drive Losses (* External signal isolation is recommended for non-isolated gate driver ICs.)

Two-Level Gate Drive Conditions

Parameter	Symbol Conditions	Canditions		Values		
Parameter		Conditions	min.	Optimum	max.	
Supply Voltage, High Level Driver	$V_{CC}(V_{GH}^{\dagger})$		15	17	V	
Supply Voltage, Low Level Driver	$V_{CC}(V_{GL}^{\dagger})$		5	5.7	V	
Negative Supply Voltage	V_{EE}		-10	-5	V	
Output Current, Peak	l _{out}	Package Limited,	1.0	1.5	Α	
Output Current, Continuous	I _{OUT}	I _D = 4.0 A, T = 175 °C	0.3	0.4	Α	

Output Gate Components

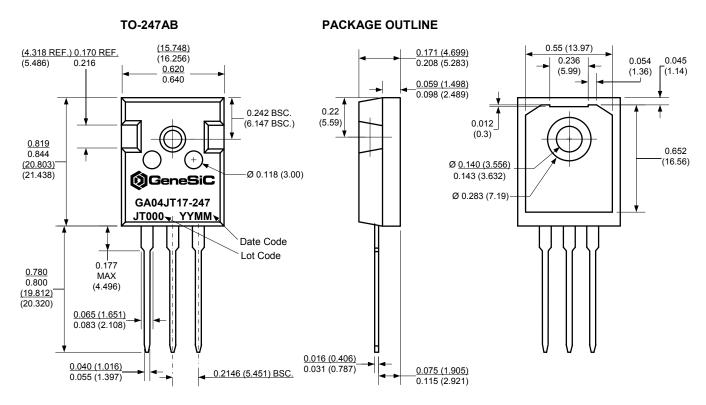
Gate Resistance	R_G	$V_{GL} = 5.7 \text{ V}, I_{G} \approx 0.4 \text{ A}, T = 175 ^{\circ}\text{C}$		1.6	5	Ω
Gate Capacitance	C_{G}	V_{GH} = 17 V, $I_{G,pk} \approx 1.5$ A, T = 175 °C	5	9		nF
Base Resistor	R₀			10		Ω
NPN/PNP BJT Output Buffer	Q_1, Q_2	2N6107/2N6292	pair or	eguivalent**		

^{** -} Complimentary BJT pair with $I_C \ge 5$ A and $V_{CEO} \ge 60$ V

⁺ – Consult application note AN-10B for more information on parameters V_{GH} and V_{GL} .



Package Dimensions:



NOTE

- 1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
- 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History						
Date	Revision	Comments	Supersedes			
2014/02/05	5	Updated Electrical Characteristics				
2013/12/18	4	Updated Gate Drive Section				
2013/11/12	3	Updated Electrical Characteristics				
2013/06/24	2	Updated Electrical Characteristics				
2013/02/21	1	Revised electrical characteristics				
2012/12/03	0	Initial release				

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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/products-sic/sjt/GA04JT17-247-SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA04JT17-247.

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MODEL OF GeneSiC Semiconductor Inc.
     $Revision: 1.0
                                $
     $Date: 26-AUG-2013
    GeneSiC Semiconductor Inc.
    43670 Trade Center Place Ste. 155
    Dulles, VA 20166
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model GA04JT17 NPN
+ IS
      1.22E-47
+ ISE
          3.91E-27
+ EG
          3.2
+ BF
          58
         0.55
+ BR
         200
+ IKF
+ NF
         2.022
+ NE
+ RB
         0.26
+ RE
         0.131970371
+ RC
         0.358
+ CJC
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+ VJC
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+ MJC
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+ CJE
          3.36E-10
+ VJE
         2.944816511
        0.493905327
+ MJE
+ XTI
         3
+ XTB
          -1.16
+ TRC1
          8.00E-3
+ VCEO
         1700
+ ICRATING 4
      GeneSiC_Semiconductor
+ MFG
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* End of GA04JT17 SPICE Model